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Substitute Form PTO-1449 (Modified)			Application No. 10/754,542	
Information Discl by App		Applicant Hajime Kimura		
(Use several sheets if necessary)		Filing Date	Group Art Unit	
(37 CFR §1.98(b))		January 12, 2004	2879	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
/JW/	AA	6,618,029	09/09/2003	Ozawa	1		07/01/1998
/JW/	AB	2003/0151568	08/14/2003	Ozawa			02/19/2003
/JW/	AC	2003/0193493	10/16/2003	Ozawa			06/10/2003
/JW/	AD	2005/0052371	03/10/2005	Ozawa			10/21/2004
/JW/	AE	6,583,805	06/24/2003	Mashimo et al.			05/28/1999
/JW/	AF	6,121,726	09/19/2000	Codama et al.			12/16/1997
/JW/	AG	6,396,208	05/28/2002	Oda et al.			01/27/1999

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No
/JW/	AH	EP 0 935 229	08/11/1999	EPO		ackslash	In English
/JW/	AI	EP 1 505 650	02/09/2005	EPO		V	In English
/JW/	AJ	EP 1 505 651	02/09/2005	EPO		X	In English
/JW/	AK	EP 1 505 652	02/09/2005	EPO		/\	In English
/JW/	AL	EP 0 849 979	06/24/1998	EPO		$/ \setminus$	In English
/JW/	AM	JP 10-208875	08/07/1998	Japan			ABS
/JW/	AN	JP 07-142169	06/02/1995	Japan	1		ABS
/JW/	AO	JP 11-024606	01/29/1999	Japan			ABS
/JW/	AP	JP 2000- 284705	10/13/2000	Japan			ABS
/JW/	AQ	JP 08-083688	03/26/1996	Japan			ABS
/JW/	AR	JP 11-354279	12/24/1999	Japan			ABS
/JW/	AS	JP 11-354271	12/24/1999	Japan			ABS
/JW/	AT	JP 10-177895	06/30/1998	Japan			ABS
/.IW/	AU	JP 11-214162	08/06/1999	Japan	/		ABS

/Joseph Williams/ (01/28/2008)

ı	Examiner Signature	Date Considered
	EXAMINER: Initials citation considered. Draw line through citation if no	t in conformance and not considered. Include copy of this form with
	next communication to applicant.	**
		Substitute Disclosure Form (PTO-1449)